An All-Digital Duty-Cycle Corrector with Synchronous and High Accuracy Output for DDR-SDRAM Application

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Abstract

A synchronous and high accuracy all-digital duty-cycle corrector (ADDCC) is presented in this paper. The proposed ADDCC utilizes simplified dual-loop architecture for synchronous and high accuracy output. The measurement results show proposed ADDCC can operate from 300 MHz to 600 MHz with input duty-cycle range 40~60%, and the output duty-cycle error is less than 1% with a RMS jitter of 3.86 ps.

1. Introduction

In modern high-speed circuits and systems, a clock with accurate 50% duty-cycle is very important. These applications, such as double data rate (DDR) memory and SDRAM, utilize both rising and falling edge of clock to double data rate. Therefore, a duty-cycle corrector (DCC) is required to ensure 50% duty-cycle clock [1]-[4]. In this paper, a feedback all-digital duty-cycle corrector (ADDCC) with synchronous and high accuracy output is presented. The proposed ADDCC utilizes simplified dual-loop architecture to achieve a synchronous and accurate 50% duty-cycle output.

2. Proposed All-Digital Duty-Cycle Corrector

The proposed ADDCC exploits a simplified dual-loop architecture, namely control loop and delay loop, as shown in Fig. 1. To explain the operation principle, a timing diagram of proposed ADDCC is shown in Fig. 2. Initially, signal Q clk is set to high by signal Ini clk. When input clock Ref clk is activated, the rising edge triggers D flip-flop (DFF) to change signal Q clk from high to low. According to the control code F[6:0], the digital-controlled delay line (DCDL) generates a varied delay clock Out clk from Q clk and triggers the pulse generator (PG). After that, the PG outputs a narrow pulse and sets signal Q clk and Out clk back to high. Until now, the delay loop completes first period of Out clk and waits for Ref clk input again. In the control loop, the phase detector (PD) outputs signal Up and Dn by compares phase of signal Ref clk and Out clk. After that, the control circuit (CC) converts pulse signal Up and Dn to up/dn counter control signal Upc and Dnc and adjust the delay of DCDL by 7-bit control code F[6:0]. After several cycle, the output signal Out clk is synchronous with input clock Ref clk. Meanwhile, the output period is just twice of delay of DCDL, ensure a 50% duty-cycle output. Therefore, due to simplified dual-loop architecture, a synchronous and high accuracy 50% duty-cycle output is provided.

3. Experimental Results

The proposed ADDCC has been fabricated in a 0.18-µm CMOS process with a 1.8-V supply voltage. Fig. 3 shows the die photo of proposed ADDCC; the active area is only 0.091 mm². As shown in Fig. 4 and Fig. 5, the output duty-cycle at 600 MHz input clock with 40% and 60% duty-cycle is 50.19% and 50.15%, respectively. And the static phase error is 26.93 ps and 18.84 ps, respectively. Additionally, the peak-to-peak jitter is 28.75 ps and RMS jitter is 3.86 ps while 600 MHz input frequency and 60% input duty-cycle, as shown in Fig. 6. The variation of output duty-cycle is less than 1% when varied input frequency and duty-cycle, as shown in Fig. 7. For convenience, Table I summarizes current state-of-art all-digital DCCs [3], [4].

4. Conclusions

A synchronous and high accuracy all-digital duty-cycle corrector is presented. Due to the simplified dual-loop architecture, a synchronous output is generated and duty-cycle error is less than 1% with varied input clock frequency and duty-cycle. Therefore, the proposed ADDCC is suitable for applications such as DDR memory and SDRAM.

References

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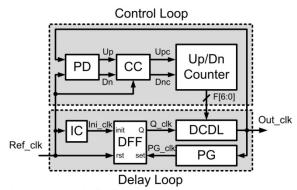


Fig. 1. Proposed all-digital synchronous duty-cycle corrector.

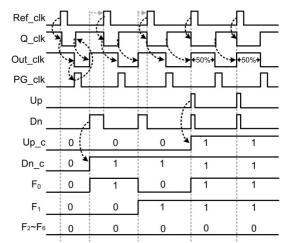


Fig. 2. Timing diagram of proposed ADDCC.

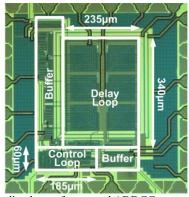


Fig. 3. The die photo of proposed ADDCC.

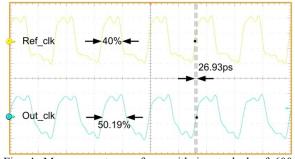


Fig. 4. Measurement waveform with input clock of $600\,$ MHz and 40% input duty-cycle.

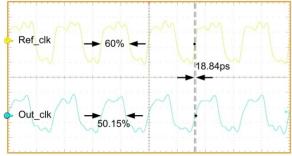


Fig. 5. Measurement waveform with input clock of 600 MHz and 60% input duty-cycle.

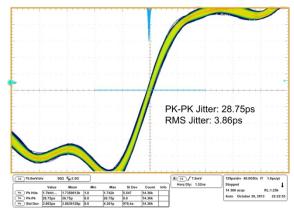


Fig. 6. Jitter histogram of corrected output at 600 MHz and 60% input duty-cycle.

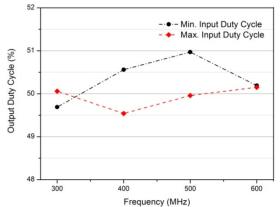


Fig. 7. Output duty-cycle range.

TABLE I. PERFORMANCE COMPARISON OF ALL-DIGITAL DCCs

	[3]	[4]	This Work
Technology	0.18 μm	0.18 μm	0.18 μm
Frequency	800 MHz	250 MHz	300 MHz
Range	~ 1.2 GHz	~ 625 MHz	~ 600 MHz
Correction Range	40% ~ 60 %	30% ~ 70%	40% ~ 60%
Duty-Cycle Error	-1.4% ~ 1.5%	< 1.6%	-0.5% ~ 1%
Jitter _{p2p} (ps)	12.9 (1.29%) @ 1 GHz	21.1 (1.74%) @ 625 MHz	28.75 (1.72%) @ 600 MHz
Jitter _{rms} (ps)	N/A	2.79 (0.17%) @ 625 MHz	3.86 (0.23%) @ 600 MHz
Power	15 mW	10.8 mW @ 625 MHz	18 mW @ 600 MHz